Docket No.: 004066 U

004066 USA/Consilium/Consilium

PATENT/OFFICIAL

IN THE UNITED STATES PATENT AND ENABLE AND ENABLE OFFICE

In re Application of

RECEIVED

John F. ARACKAPARAMBIL et al.

OCT 1 4 2004

Serial No. 09/363,966

Group Art Unit: 2125

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Technology Center 2100

Filed: July 29, 1999

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Examiner: Steven R. Garland

For:

COMPUTER INTEGRATED MANUFACTURING TECHNIQUES

SUPPLEMENTAL INFORMATION DISCLOSURE STATEMENT

Honorable Commissioner for Patents P.O. Box 1450 Alexandria, VA 22313-1450

Sir:

In accordance with the provisions of 37 C.F.R. 1.56, 1.97 and 1.98, the attention of the Patent and Trademark Office is hereby directed to the documents listed on the attached form PTO-1449. It is respectfully requested that the documents be expressly considered during the prosecution of this application, and that the documents be made of record therein and appear among the "References Cited" on any patent to issue therefrom.

This submission does not constitute a representation that a search has been made or that no better art exists and does not constitute an admission or representation that any of the listed documents is material or constitutes prior art. If it should be determined that any of the listed documents does not constitute prior art under the United States law, Applicants reserve the right to present to the Office the relevant facts and law regarding the appropriate status of such document.

10/12/2004 RFEKADU1 00000053 080219 09363966

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Serial No. 09/363,966

Please charge the fee of \$180.00 under 37 CFR 1.17(p) to Deposit Account No. 08-0219. The Commissioner is also authorized to charge any deficiency in any fees pursuant to 37 CFR § 1.17 associated with this communication and to credit any excess payment to Deposit Account No. 08-0219.

Respectfully submitted,

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Date: 0/5/04

ATTY. DOCKET NO. SERIAL NO. 09/363,966 004066 USA/ INFORMATION DISCLOSURE Consilium/Consilium RECEIVED CITATION IN AN **APPLICATION** OCT 1 4 2004 (PTO-1449) Technology Center 2100 APPLICANT John F. ARACKAPARAMBIL et al. FILING DATE GROUP July 29, 1999 2125 U.S. PATENT DOCUMENTS FILING EXAMINER'S **CLASS SUBCLASS** DATE PATENT NO. DATE NAME **INITIALS** 06/11/97 5,975,994 11/02/99 Sandhu et al. 12/18/97 6,113,462 09/05/00 Yang 06/26/98 6,230,069 B1 05/08/01 Campbell et al. 10/29/99 6,268,270 B1 07/31/01 Scheid et al. 10/09/98 6,277,014 B1 08/21/01 Chen et al. 06/01/00 09/18/01 Kelkar 6,291,367 B1 01/04/00 10/15/02 Coss, Jr. et al. 6,465,263 B1 10/29/99 03/11/03 Miller et al. 6,532,555 B1 03/05/01 03/18/03 Miller et al. 6,535,783 B1 07/31/00 6,541,401 B1 04/01/03 Herner et al. 10/29/99 Sonderman et al. 6,546,508 B1 04/08/03 09/09/99 Miller 6,556,881 B1 04/29/03 06/04/01 Wiswesser et al. 11/25/03 6,652,355 B2 07/31/00 04/20/04 Coss, Jr. et al. 6,725,402 B1

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to Applicant.

EXAMINER

DATE CONSIDERED

INFORMATION DISCLOSURE CITATION IN AN APPLICATION (PTO-1449) (PTO-1449) OTHER ART (Including Author, T	FILING DATE July 29, 1999 itle, Date, Pertinent Pages, Et	GROUP 2125
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